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(12) **United States Design Patent**  
**Barton et al.**

(10) **Patent No.:** **US D777,049 S**  
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(54) **DIAGNOSTIC ANALYZER**

OTHER PUBLICATIONS

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- (73) Assignee: **ABBOTT LABORATORIES**, Abbott Park, IL (US)

(\*\*) Term: **15 Years**

(Continued)

(21) Appl. No.: **29/531,578**

*Primary Examiner* — Antoine D Davis

(22) Filed: **Jun. 26, 2015**

(74) *Attorney, Agent, or Firm* — Hanley, Flight & Zimmerman, LLC

(51) **LOC (10) Cl.** ..... **10-04**

(57) **CLAIM**

(52) **U.S. Cl.**

The ornamental design for "diagnostic analyzer," as shown and described.

USPC ..... **D10/81**; D24/216

(58) **Field of Classification Search**

**DESCRIPTION**

USPC ..... D10/81; D24/216, 219, 220, 232, 233, D24/234

CPC G01N 21/00; G01N 21/01; G01N 2021/0106; G01N 2201/022; G01N 2201/0221; G01N 2201/0222; G01N 2201/0224; G01N 2201/0225; G01N 2201/0227; G01N 2201/0228; G01N 2201/024; G01N 2201/0245; G01N 2021/0112-21/958  
See application file for complete search history.

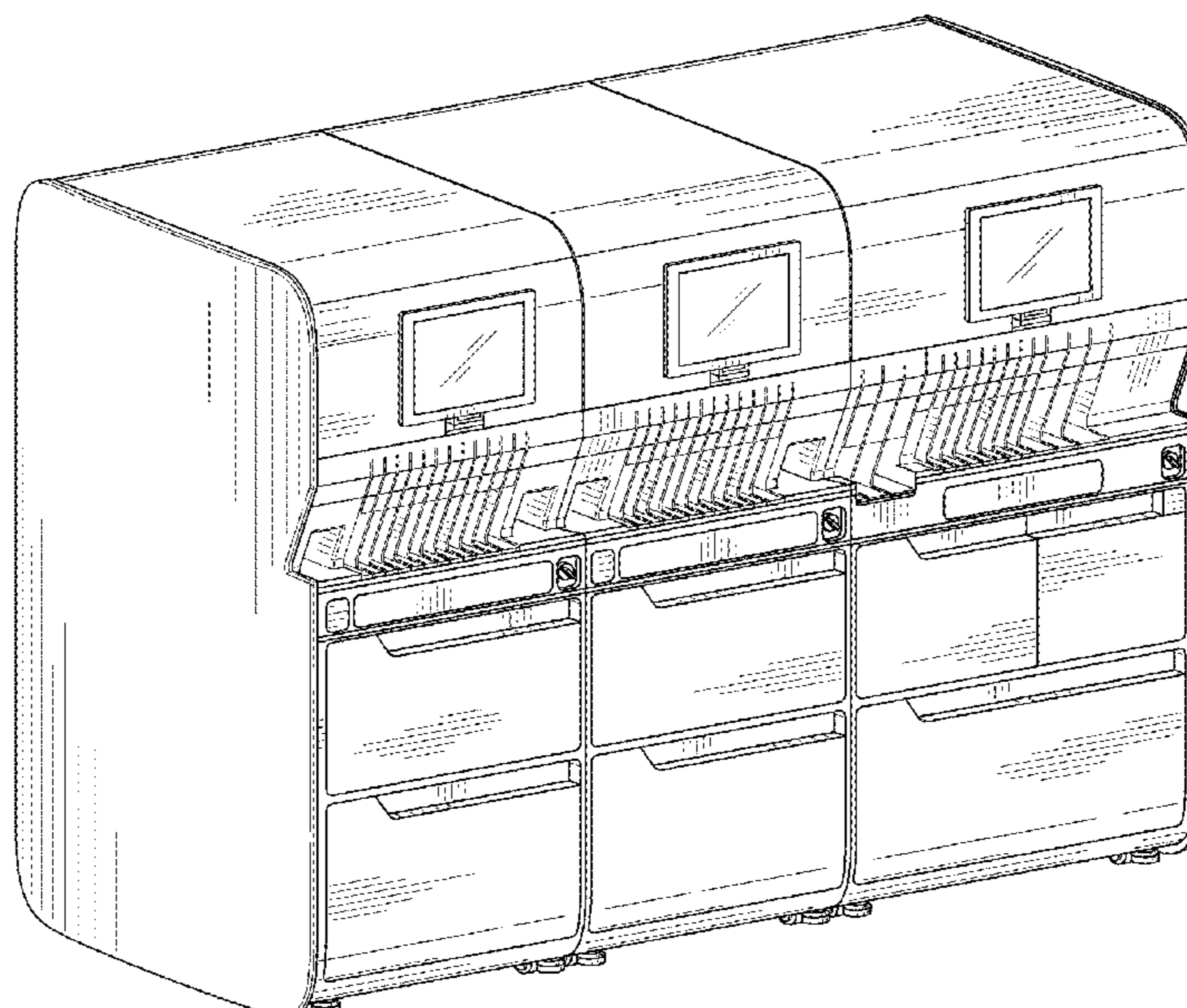
FIG. 1 is a front left perspective view of diagnostic analyzer. FIG. 2 is a front view of the diagnostic analyzer of FIG. 1. FIG. 3 is a rear view of the diagnostic analyzer of FIG. 1. FIG. 4 is a right side view of the diagnostic analyzer of FIG. 1. FIG. 5 is a left side view of the diagnostic analyzer of FIG. 1. FIG. 6 is a top view of the diagnostic analyzer of FIG. 1; and, FIG. 7 is a bottom view of the diagnostic analyzer of FIG. 1.

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**1 Claim, 6 Drawing Sheets**



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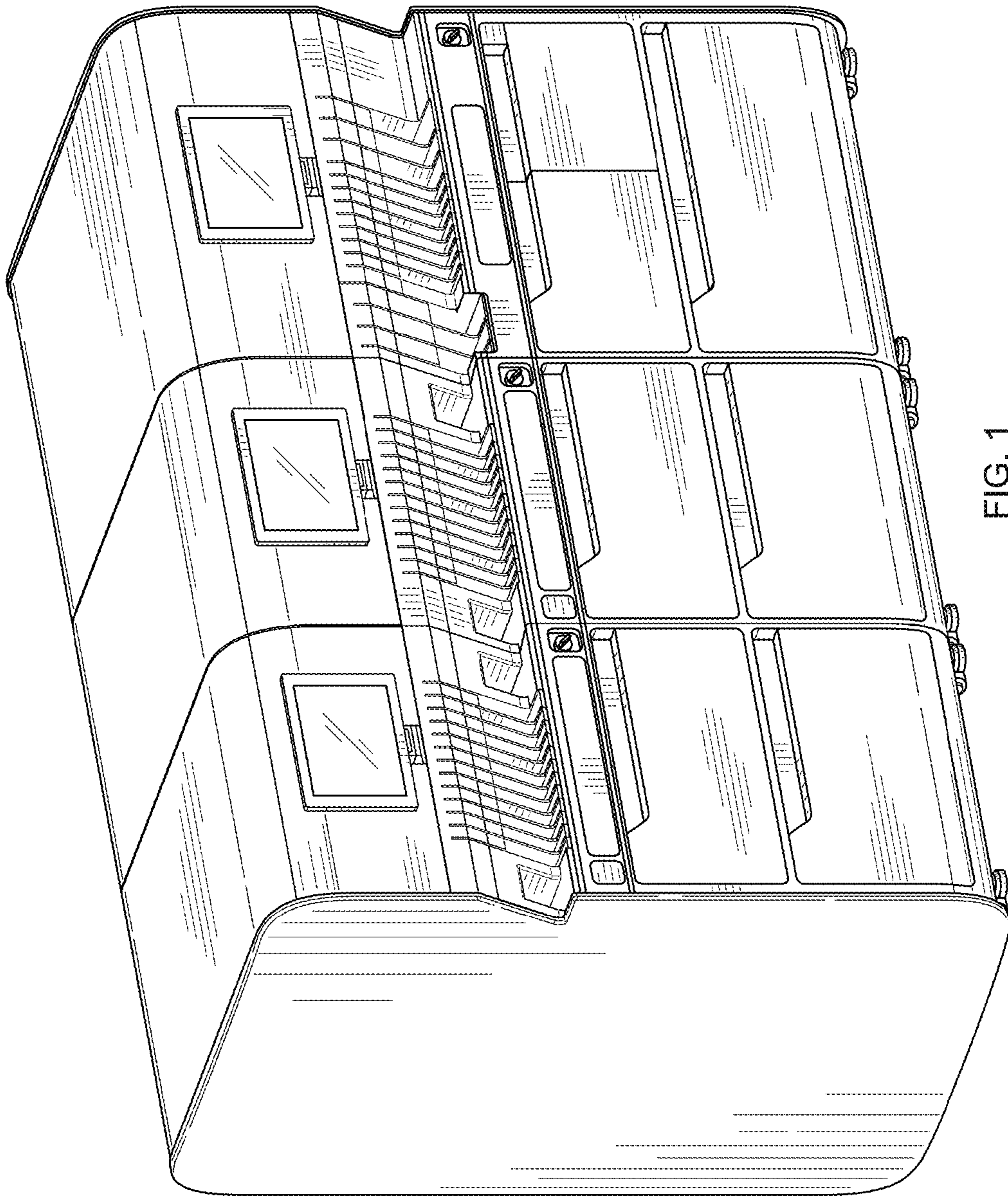


FIG. 1

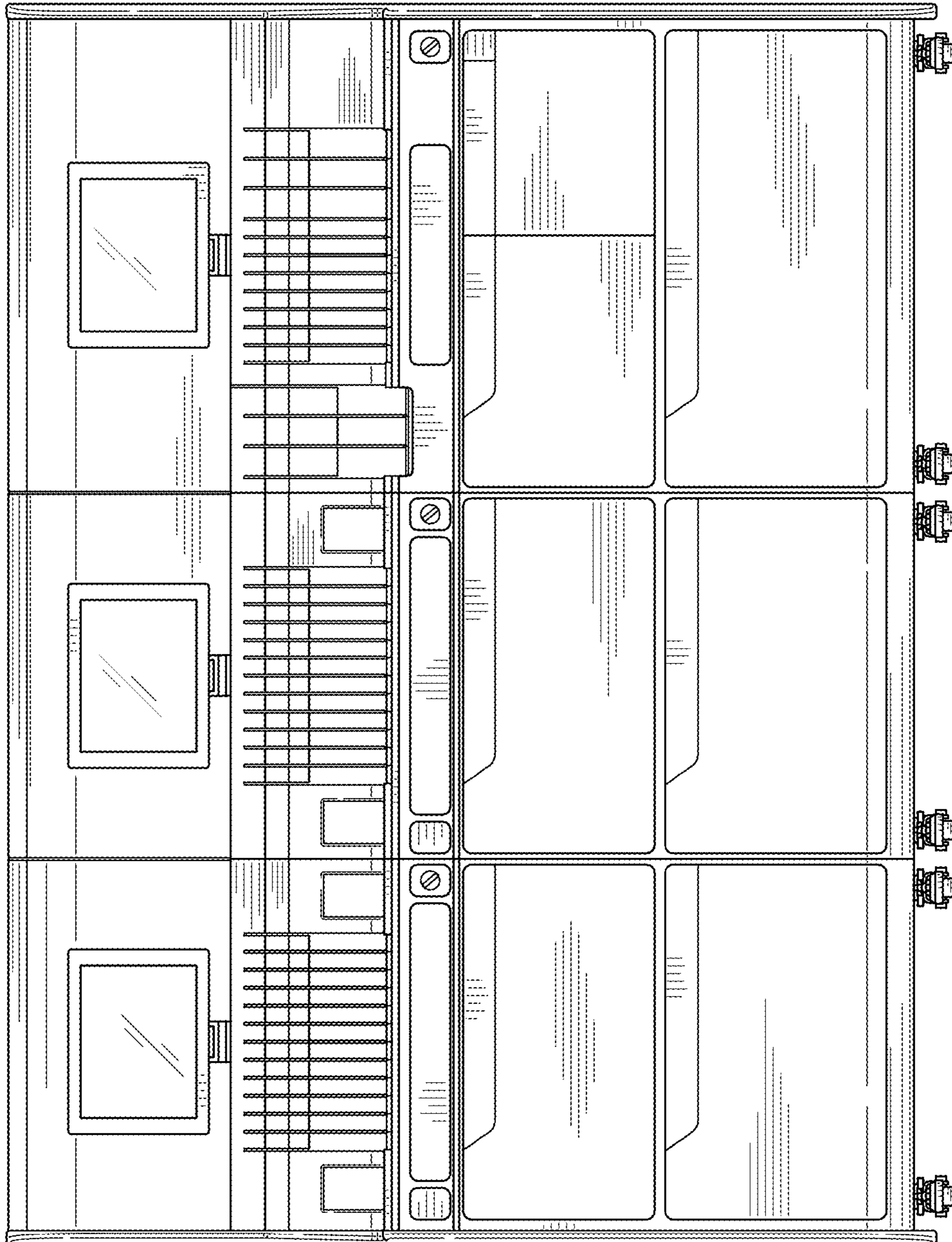


FIG. 2

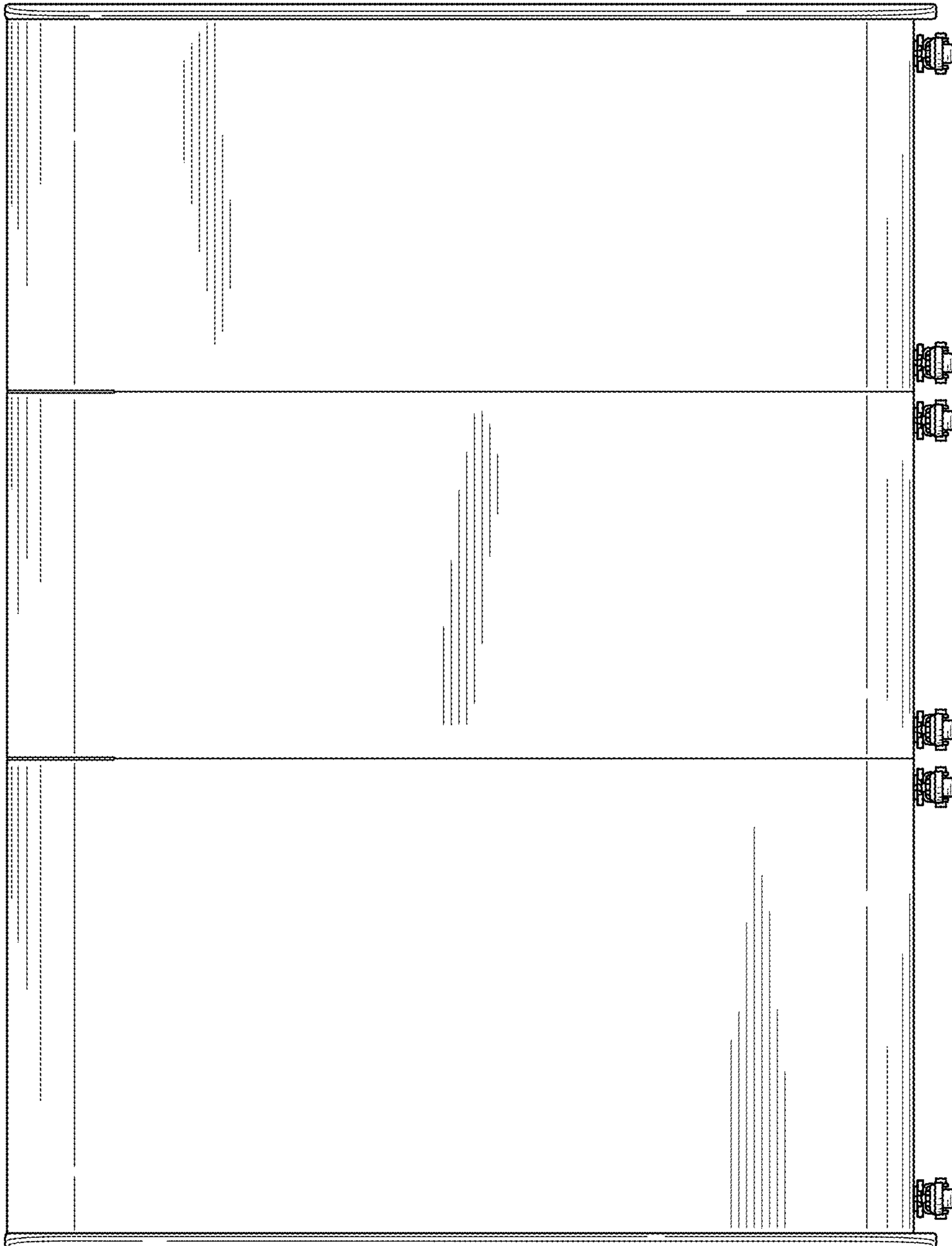


FIG. 3

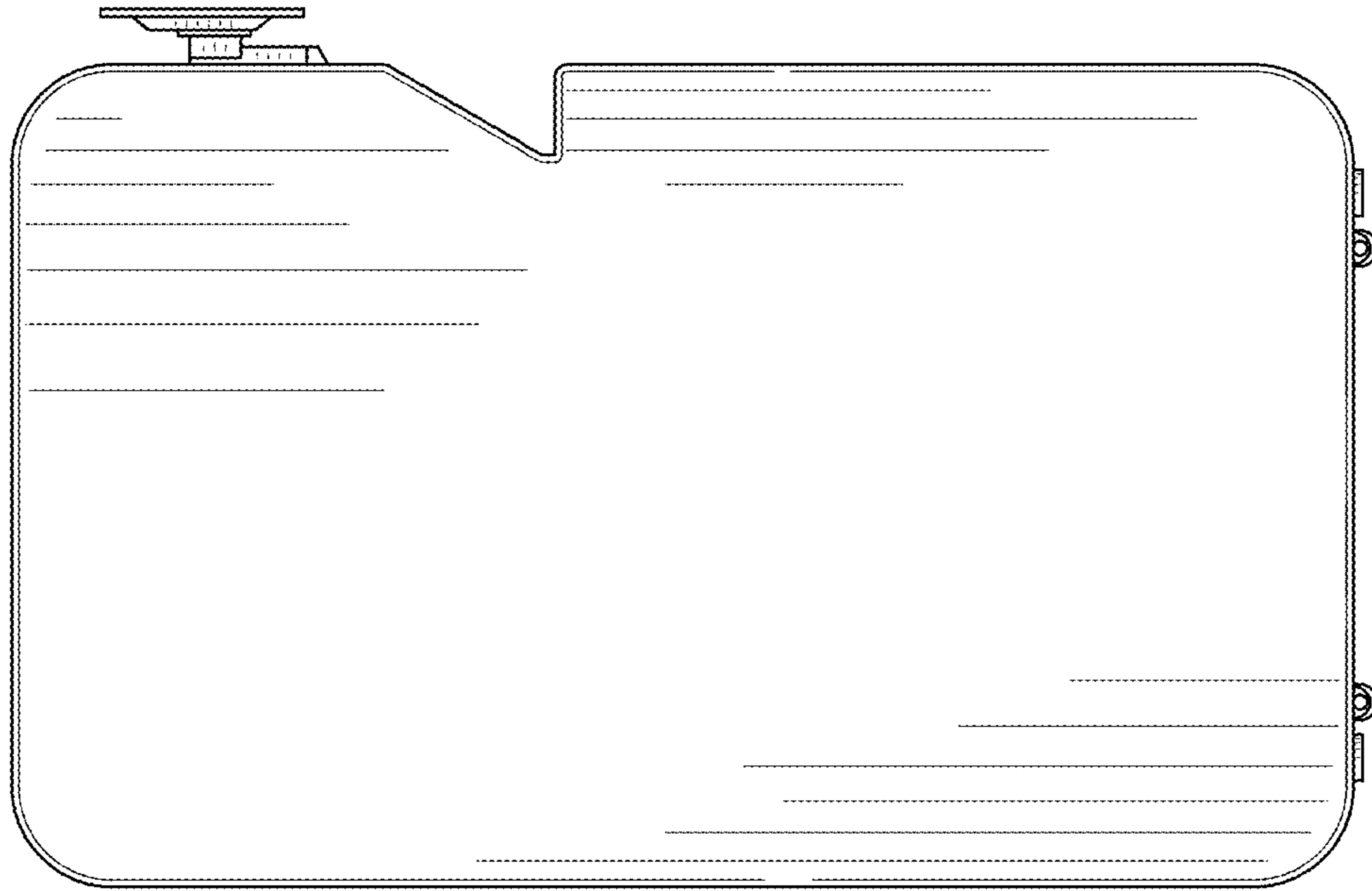


FIG. 5

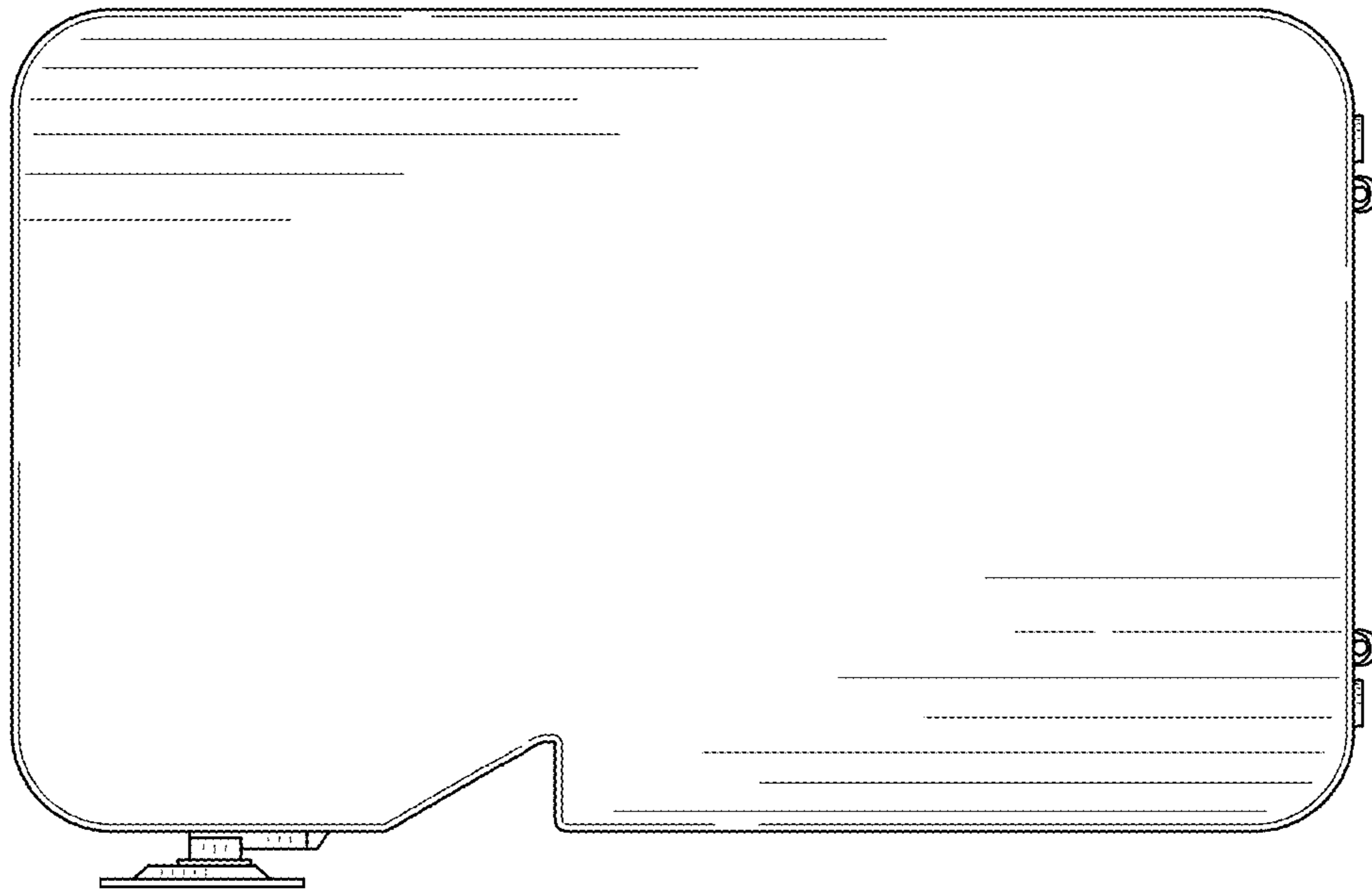


FIG. 4

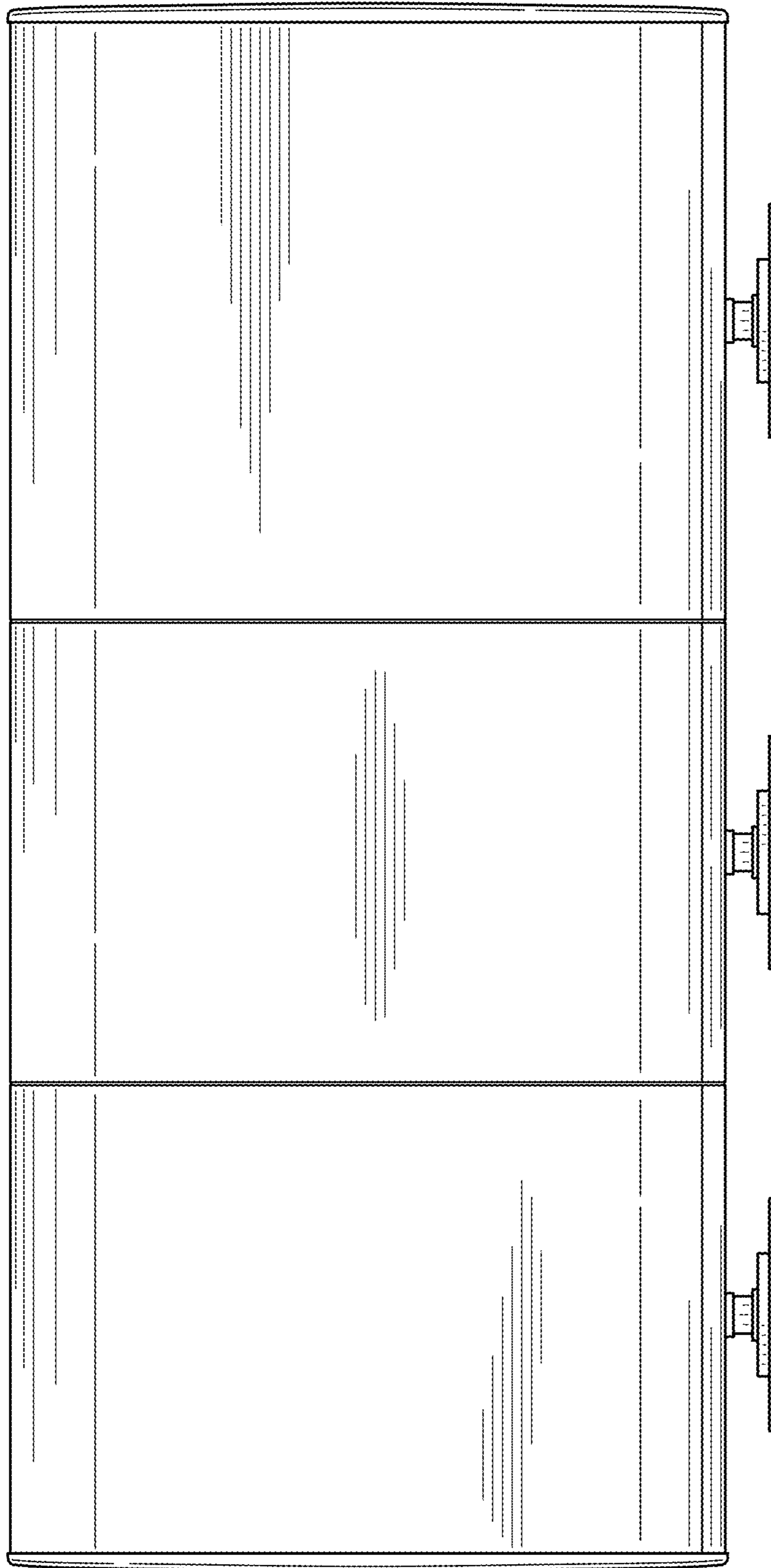


FIG. 6

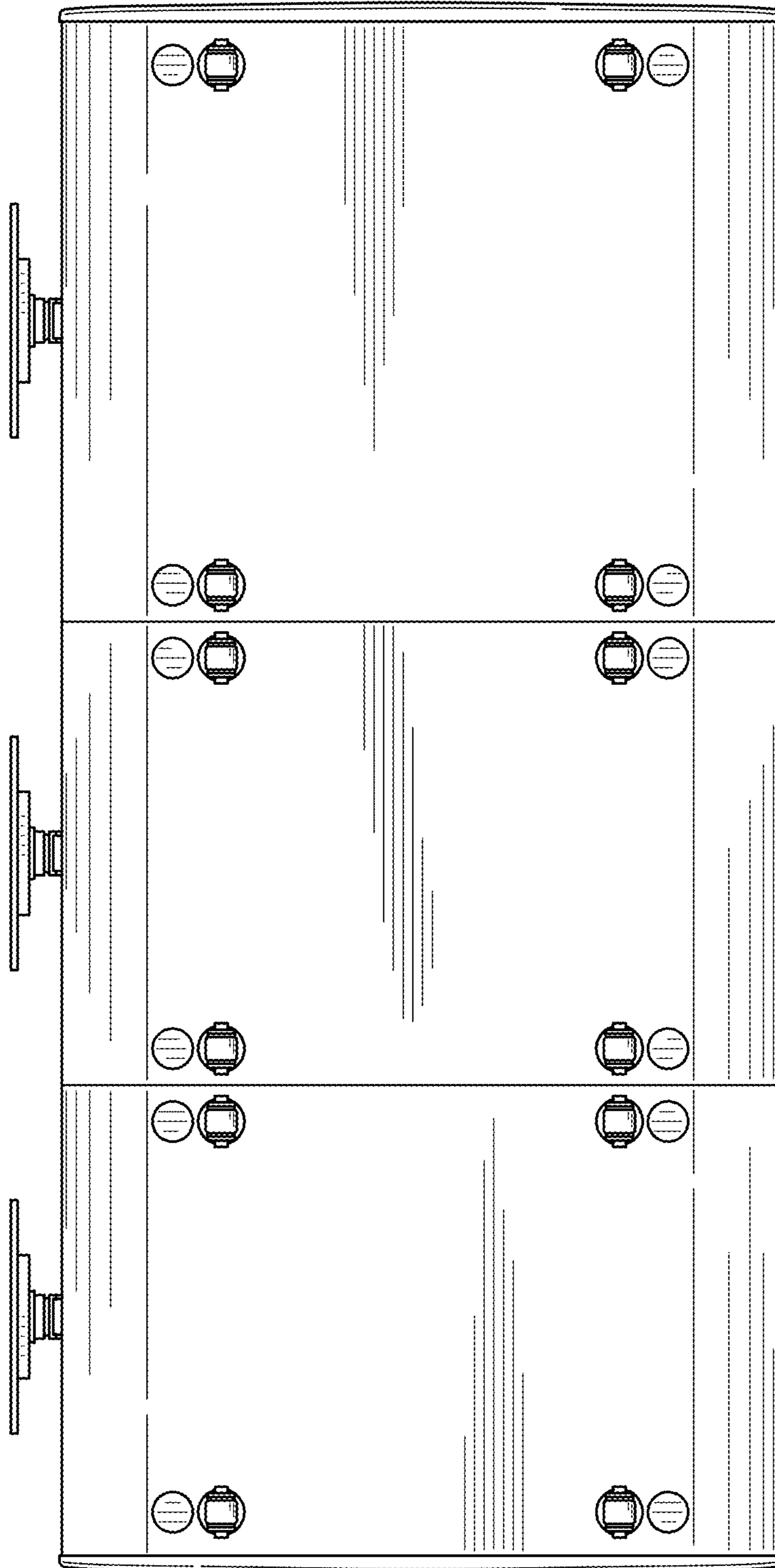


FIG. 7